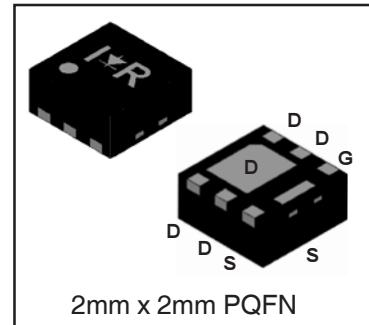
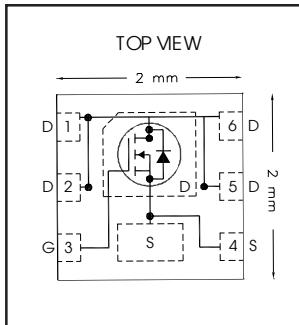


HEXFET® Power MOSFET

V_{DS}	25	V
V_{GS} max	± 20	V
$R_{DS(on)}$ max (@ $V_{GS} = 10V$)	13.0	$m\Omega$
Q_g (typical) (@ $V_{GS} = 4.5V$)	4.3	nC
I_D (@ $T_{c(Bottom)} = 25^\circ C$)	8.5②	A



Applications

- System/Load Switch

Features and Benefits

Features

Low $R_{DS(on)}$ ($\leq 13.0m\Omega$)
Low Thermal Resistance to PCB ($\leq 13^\circ C/W$)
Low Profile (≤ 1.0 mm)
Compatible with Existing Surface Mount Techniques
RoHS Compliant Containing no Lead, no Bromide and no Halogen
MSL1, Industrial Qualification

Resulting Benefits

Lower Conduction Losses
Enable better thermal dissipation
Increased Power Density
Easier Manufacturing
Environmentally Friendlier
Increased Reliability

results in

Orderable part number	Package Type	Standard Pack		Note
		Form	Quantity	
IRFHS8242TRPbF	PQFN 2mm x 2mm	Tape and Reel	4000	
IRFHS8242TP2PbF	PQFN 2mm x 2mm	Tape and Reel	400	EOL notice # 259

Absolute Maximum Ratings

	Parameter	Max.	Units
V_{DS}	Drain-to-Source Voltage	25	V
V_{GS}	Gate-to-Source Voltage	± 20	
I_D @ $T_A = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	9.9②	A
I_D @ $T_A = 70^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	8.0	
I_D @ $T_{c(Bottom)} = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	21②	A
I_D @ $T_{c(Bottom)} = 70^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	17②	
I_D @ $T_{c(Bottom)} = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$ (Package Limited)	8.5②	A
I_{DM}	Pulsed Drain Current ①	84	
P_D @ $T_A = 25^\circ C$	Power Dissipation ④	2.1	W
P_D @ $T_A = 70^\circ C$	Power Dissipation ④	1.3	
	Linear Derating Factor ④	0.02	W/ $^\circ C$
T_J T_{STG}	Operating Junction and Storage Temperature Range	-55 to + 150	$^\circ C$

Notes ① through ④ are on page 2

Static @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	25	—	—	V	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$
$\Delta \text{BV}_{\text{DSS}/\Delta T_J}$	Breakdown Voltage Temp. Coefficient	—	18	—	$\text{mV}/^\circ\text{C}$	Reference to $25^\circ\text{C}, I_D = 1\text{mA}$
$R_{\text{DS(on)}}$	Static Drain-to-Source On-Resistance	—	10.0	13.0	$\text{m}\Omega$	$V_{\text{GS}} = 10\text{V}, I_D = 8.5\text{A}$ ③②
		—	17.0	21.0		$V_{\text{GS}} = 4.5\text{V}, I_D = 6.8\text{A}$ ③
$V_{\text{GS(th)}}$	Gate Threshold Voltage	1.35	1.8	2.35	V	$V_{\text{DS}} = V_{\text{GS}}, I_D = 25\mu\text{A}$
$\Delta V_{\text{GS(th)}}$	Gate Threshold Voltage Coefficient	—	-6.8	—	$\text{mV}/^\circ\text{C}$	
I_{DSS}	Drain-to-Source Leakage Current	—	—	1.0	μA	$V_{\text{DS}} = 20\text{V}, V_{\text{GS}} = 0\text{V}$
		—	—	150		$V_{\text{DS}} = 20\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 125^\circ\text{C}$
I_{GSS}	Gate-to-Source Forward Leakage	—	—	100	nA	$V_{\text{GS}} = 20\text{V}$
	Gate-to-Source Reverse Leakage	—	—	-100		$V_{\text{GS}} = -20\text{V}$
g_{fs}	Forward Transconductance	19	—	—	S	$V_{\text{DS}} = 10\text{V}, I_D = 8.5\text{A}$ ②
Q_g	Total Gate Charge ⑥	—	4.3	—	nC	$V_{\text{GS}} = 4.5\text{V}, V_{\text{DS}} = 13\text{V}, I_D = 8.5\text{A}$ ②
Q_g	Total Gate Charge ⑥	—	10.4	—	nC	$V_{\text{DS}} = 13\text{V}$
Q_{gs}	Gate-to-Source Charge ⑥	—	1.8	—		$V_{\text{GS}} = 10\text{V}$
Q_{gd}	Gate-to-Drain Charge ⑥	—	1.6	—		$I_D = 8.5\text{A}$ ② (See Fig. 6 & 16)
R_G	Gate Resistance	—	1.9	—		Ω
$t_{\text{d(on)}}$	Turn-On Delay Time	—	6.5	—	ns	$V_{\text{DD}} = 13\text{V}, V_{\text{GS}} = 4.5\text{V}$ ③
t_r	Rise Time	—	19	—		$I_D = 8.5\text{A}$ ②
$t_{\text{d(off)}}$	Turn-Off Delay Time	—	5.4	—		$R_G = 1.8\Omega$
t_f	Fall Time	—	5.3	—		See Fig. 17
C_{iss}	Input Capacitance	—	653	—	pF	$V_{\text{GS}} = 0\text{V}$
C_{oss}	Output Capacitance	—	171	—		$V_{\text{DS}} = 10\text{V}$
C_{rss}	Reverse Transfer Capacitance	—	78	—		$f = 1.0\text{MHz}$

Diode Characteristics

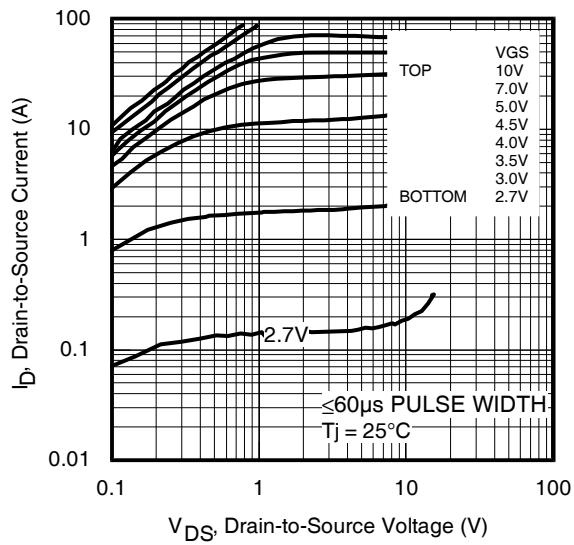
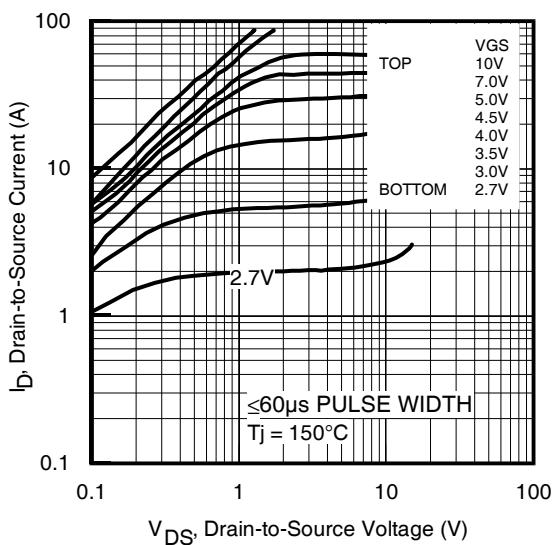
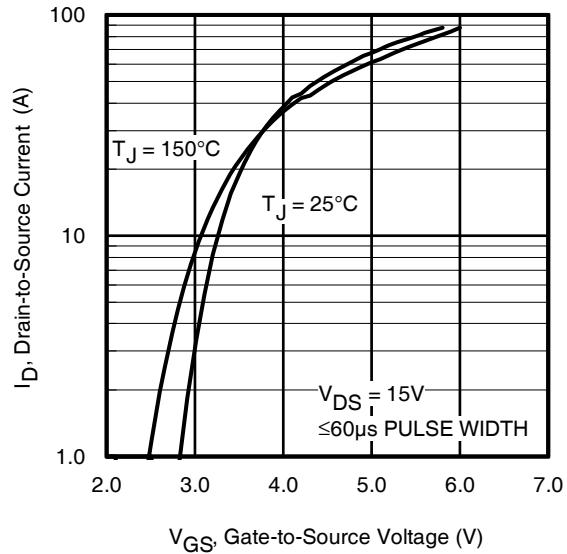
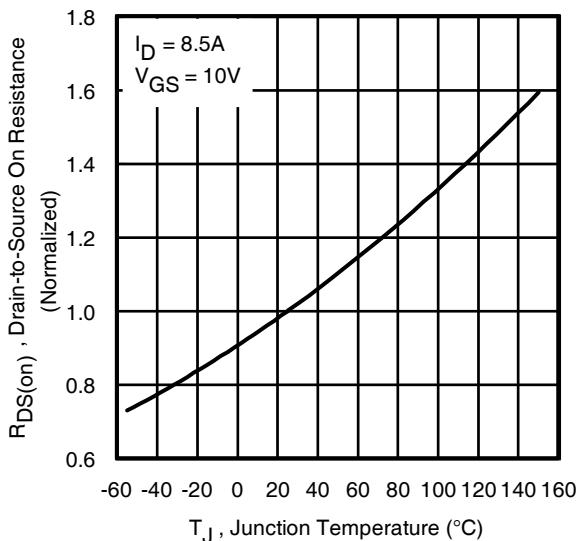
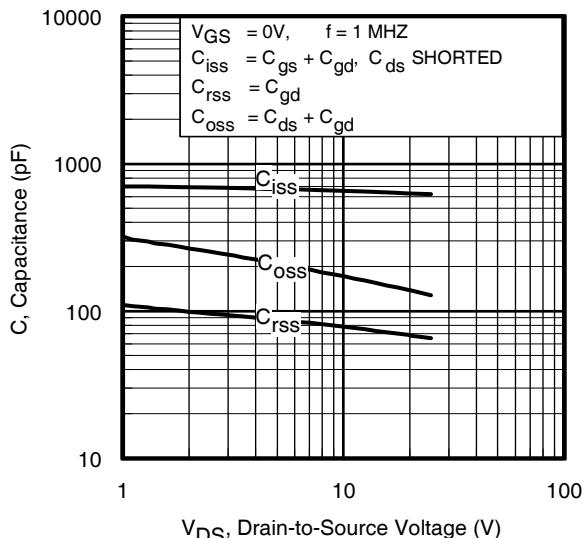
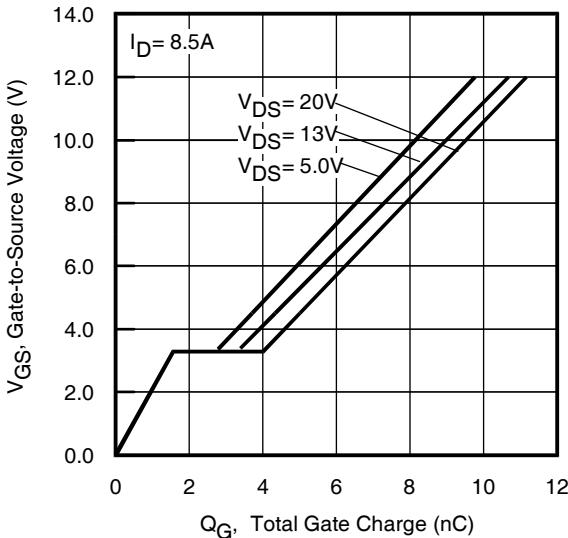
	Parameter	Min.	Typ.	Max.	Units	Conditions
I_S	Continuous Source Current (Body Diode)	—	—	8.5②	A	MOSFET symbol showing the integral reverse p-n junction diode.
I_{SM}	Pulsed Source Current (Body Diode) ①	—	—	84		
V_{SD}	Diode Forward Voltage	—	—	1.0	V	$T_J = 25^\circ\text{C}, I_S = 8.5\text{A}$ ②, $V_{\text{GS}} = 0\text{V}$ ③
t_{rr}	Reverse Recovery Time	—	11	17	ns	$T_J = 25^\circ\text{C}, I_F = 8.5\text{A}$ ②, $V_{\text{DD}} = 13\text{V}$
Q_{rr}	Reverse Recovery Charge	—	11	17	nC	$\text{di/dt} = 280 \text{ A}/\mu\text{s}$ ③
t_{on}	Forward Turn-On Time	Time is dominated by parasitic Inductance				

Thermal Resistance

	Parameter	Typ.	Max.	Units
$R_{\theta\text{JC}}$ (Bottom)	Junction-to-Case ⑤	—	13	$^\circ\text{C}/\text{W}$
$R_{\theta\text{JC}}$ (Top)	Junction-to-Case ⑤	—	90	
$R_{\theta\text{JA}}$	Junction-to-Ambient ④	—	60	
$R_{\theta\text{JA}}$	Junction-to-Ambient (<10s) ④	—	42	

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Current limited by package.
- ③ Pulse width $\leq 400\mu\text{s}$; duty cycle $\leq 2\%$.
- ④ When mounted on 1 inch square copper board
- ⑤ R_θ is measured at T_J of approximately 90°C .
- ⑥ For DESIGN AID ONLY, not subject to production testing.

**Fig 1.** Typical Output Characteristics**Fig 2.** Typical Output Characteristics**Fig 3.** Typical Transfer Characteristics**Fig 4.** Normalized On-Resistance vs. Temperature**Fig 5.** Typical Capacitance vs. Drain-to-Source Voltage**Fig 6.** Typical Gate Charge vs. Gate-to-Source Voltage

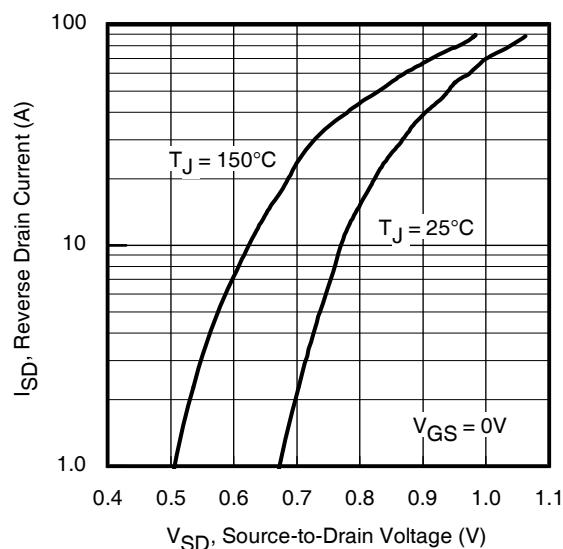


Fig 7. Typical Source-Drain Diode Forward Voltage

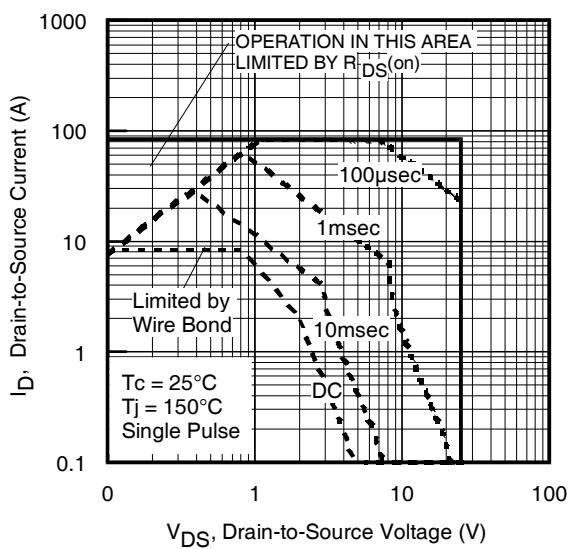


Fig 8. Maximum Safe Operating Area

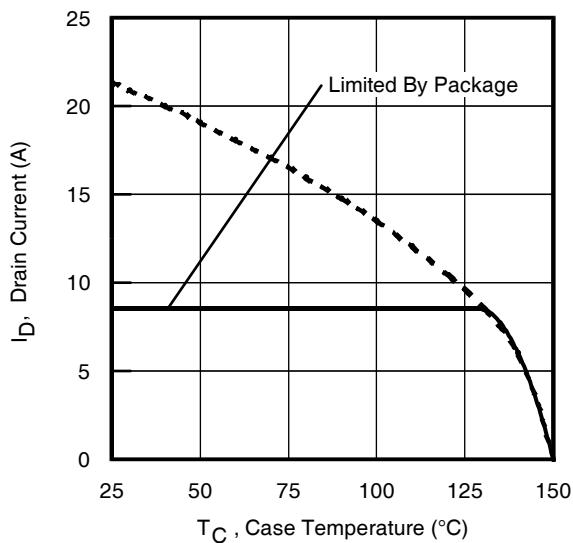


Fig 9. Maximum Drain Current vs. Case (Bottom) Temperature

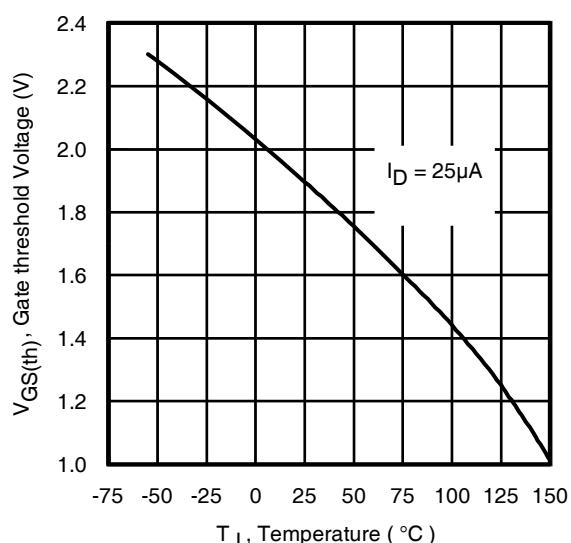


Fig 10. Threshold Voltage vs. Temperature

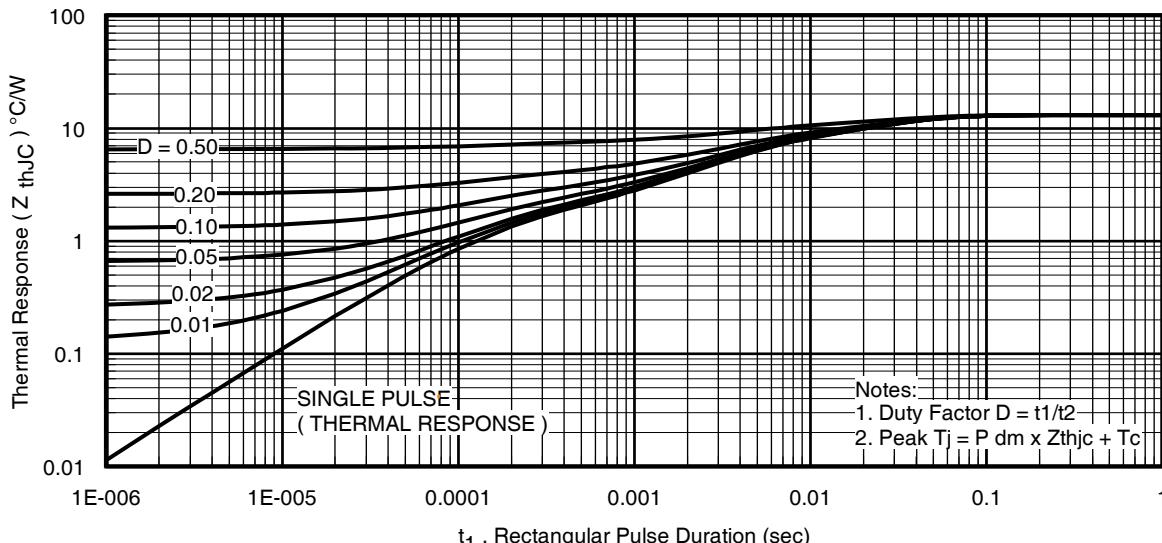


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case (Bottom)

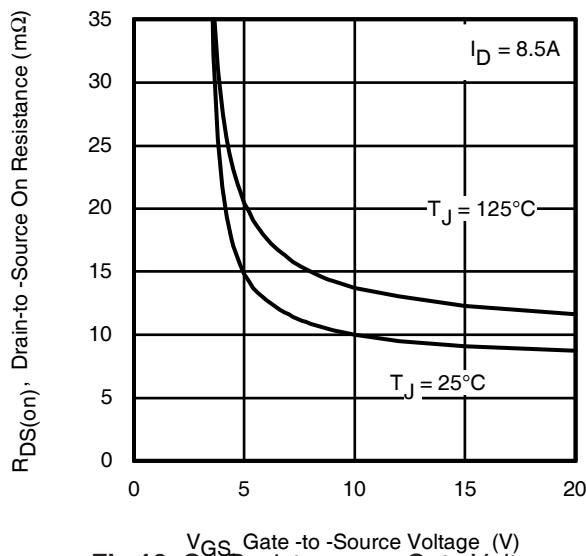


Fig 12. On-Resistance vs. Gate Voltage

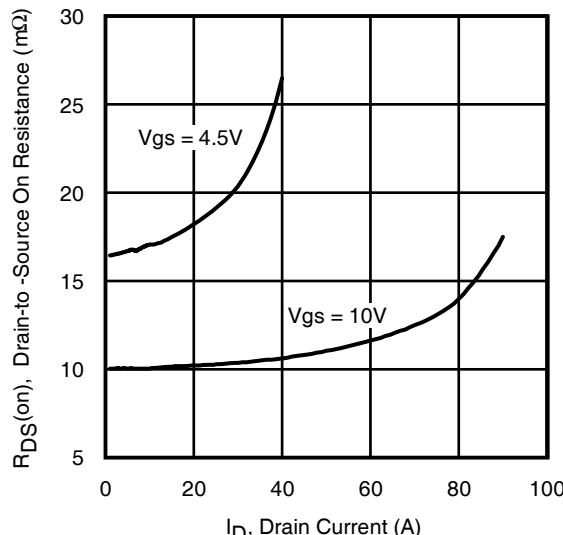


Fig 13. Typical On-Resistance vs. Drain Current

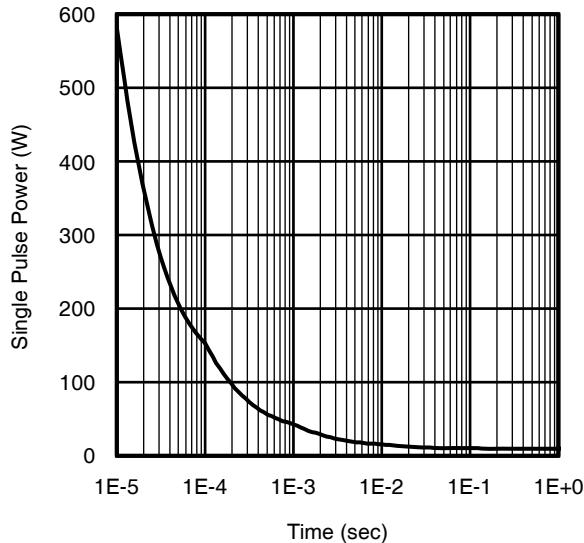


Fig 14. Typical Power vs. Time

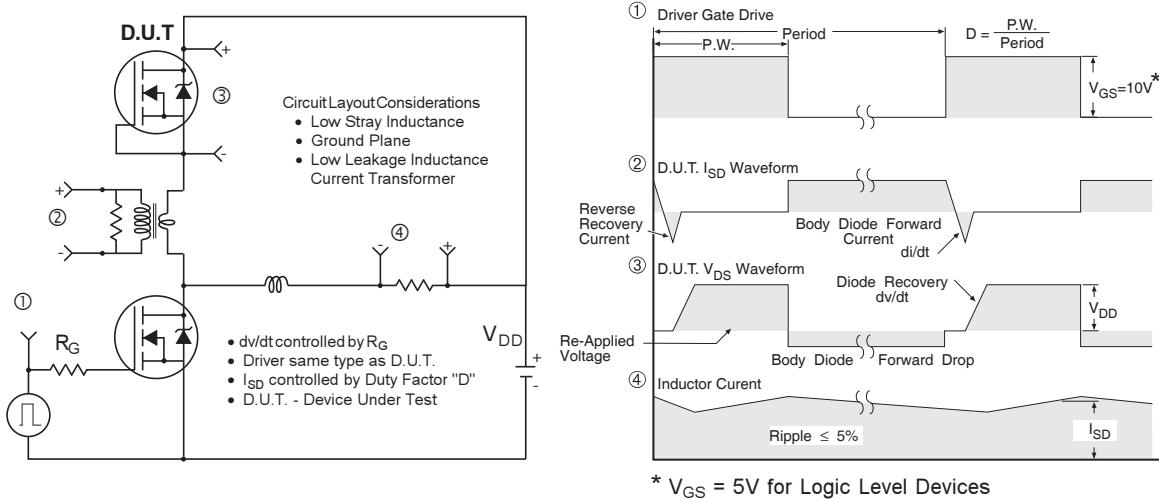
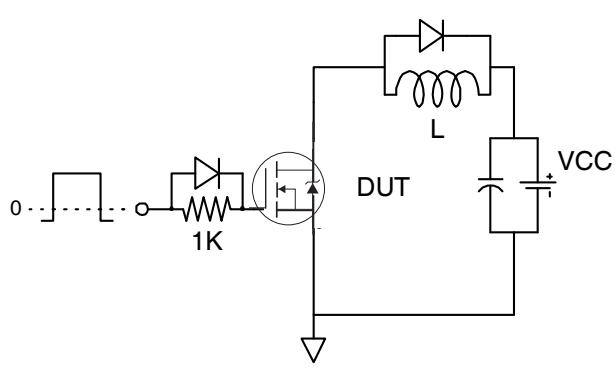
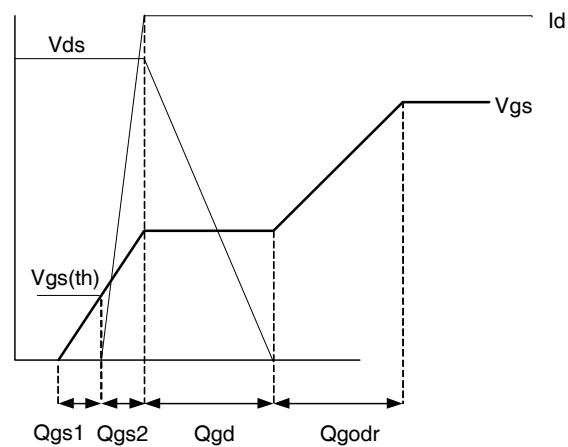
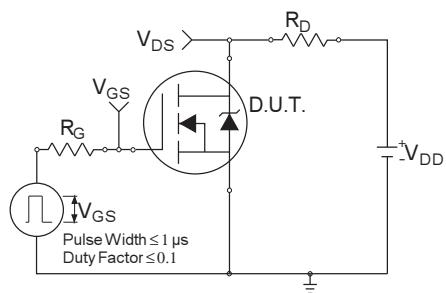
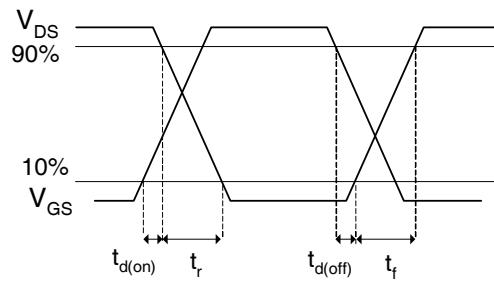
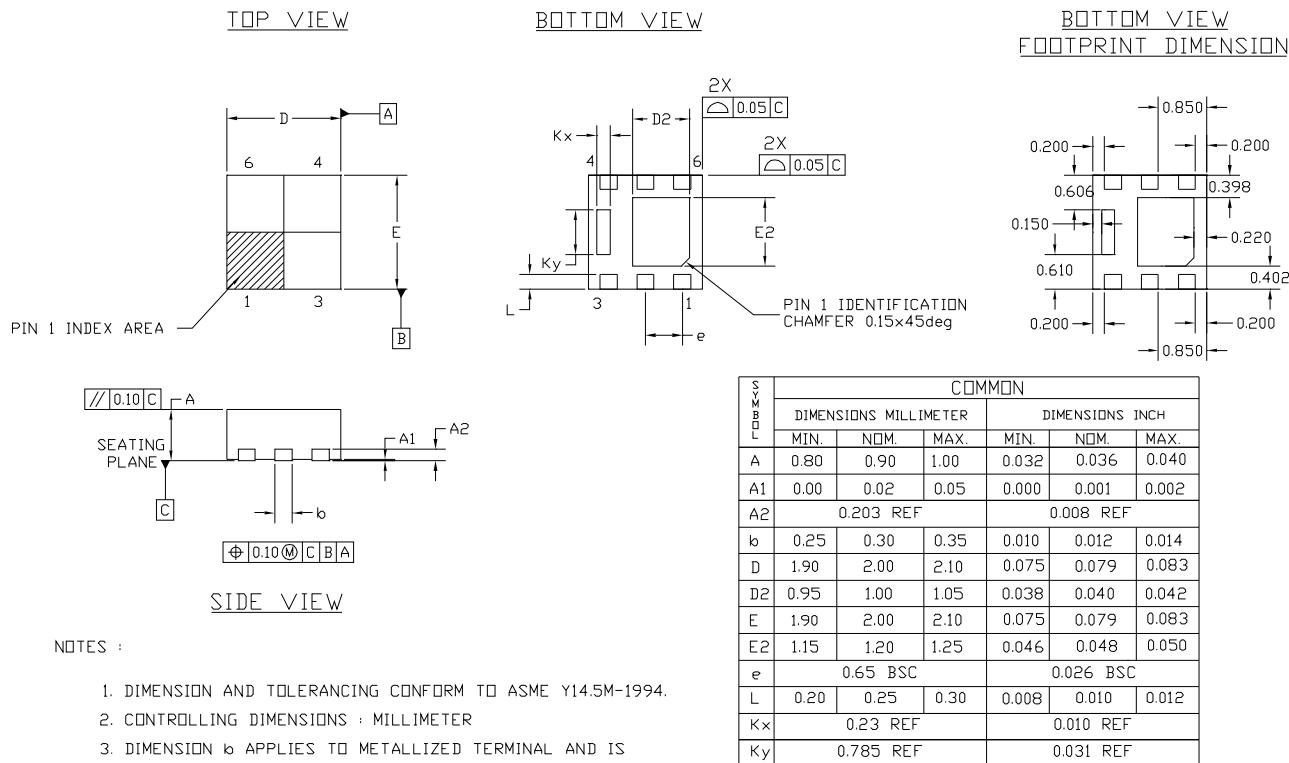


Fig 15. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

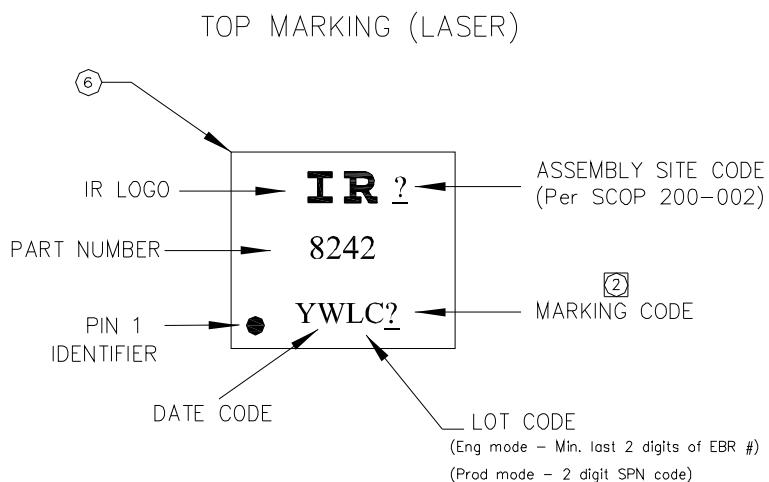
**Fig 16a.** Gate Charge Test Circuit**Fig 16b.** Gate Charge Waveform**Fig 17a.** Switching Time Test Circuit**Fig 17b.** Switching Time Waveforms

PQFN 2x2 Outline Package Details



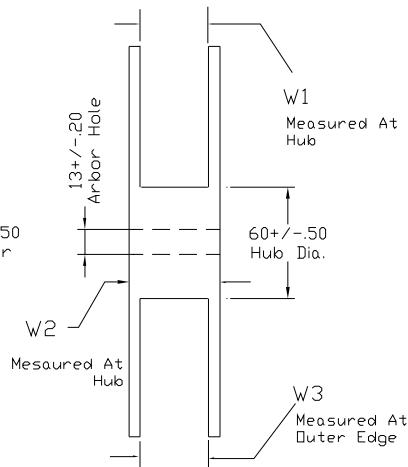
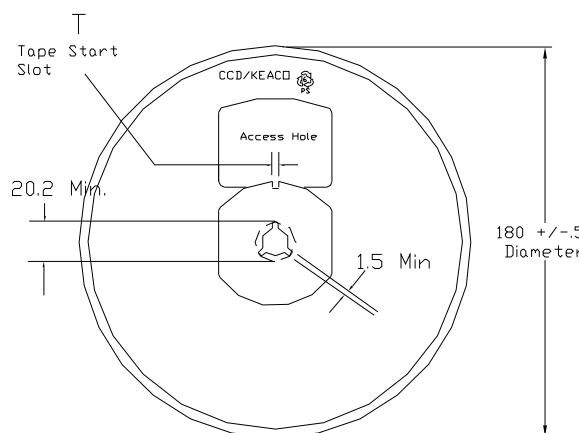
For footprint and stencil design recommendations, please refer to application note AN-1154 at <http://www.irf.com/technical-info/appnotes/an-1154.pdf>

PQFN 2x2 Outline Part Marking



Note: For the most current drawing please refer to IR website at: <http://www.irf.com/package/>

PQFN 2x2 Outline Tape and Reel



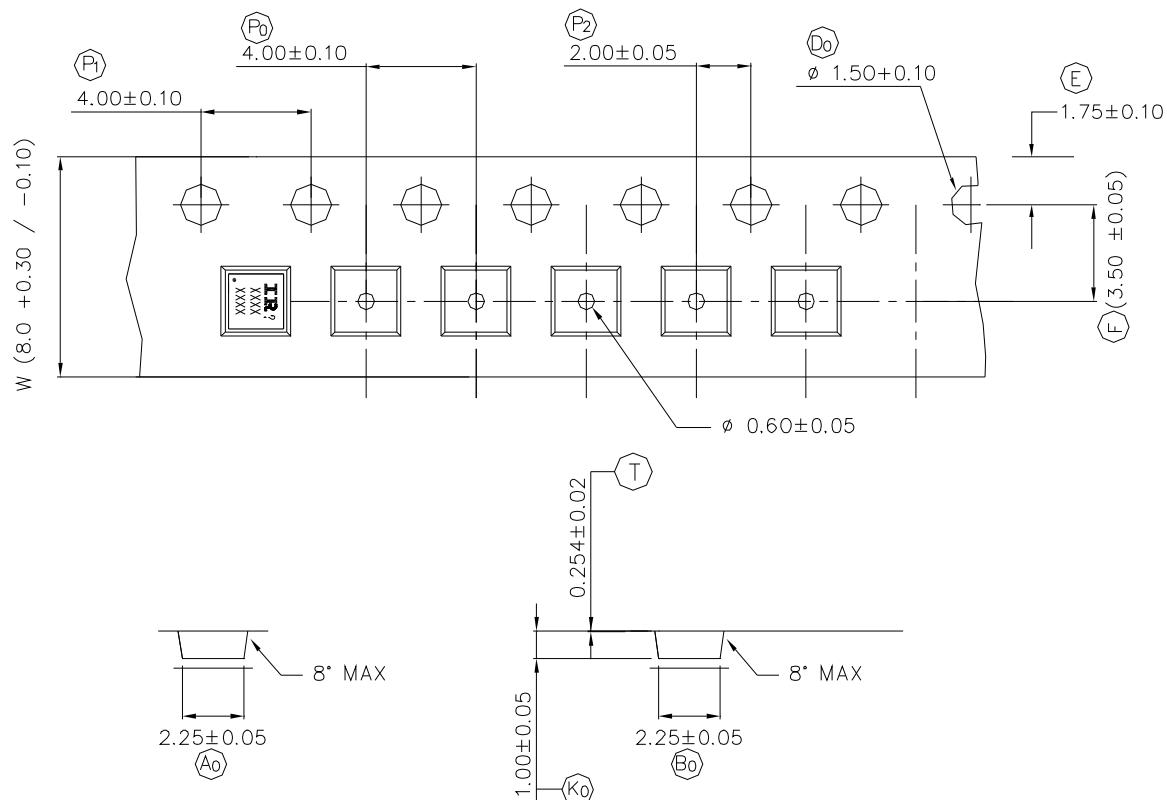
FRONT VIEW

SIDE VIEW

TABLE 1: REEL DETAILS

TAPE WIDTH	T	W1	W2	W3	PART NO
8 MM	3 ± 0.50	8.4 +1.5 -0.0	14.4 Max	7.90 Min 10.9 Max	91586-1
12 MM	5 ± 0.50	12.4 +2.0 -0.0	18.4 Max	11.9 Min 15.4 Max	91586-2

Note: Surface resistivity is $\geq 1 \times 10^5$ but $< 1 \times 10^{12}$ ohm/sq.



Note: For the most current drawing please refer to IR website at: <http://www.irf.com/package/>

Qualification information[†]

Qualification level	Industrial [†] (per JEDEC JESD47F ^{††} guidelines)	
Moisture Sensitivity Level	PQFN 2mm x 2mm	MSL1 (per JEDEC J-STD-020D ^{††})
RoHS compliant	Yes	

[†] Qualification standards can be found at International Rectifier's web site

<http://www.irf.com/product-info/reliability>

^{††} Applicable version of JEDEC standard at the time of product release.

Revision History

Date	Comments
12/17/2013	<ul style="list-style-type: none">• Updated ordering information to reflect the End-Of-life (EOL) of the mini-reel option (EOL notice #259)• Updated Qual level from "Consumer" to "Industrial" on page 1, 9• Updated data sheet with new IR corporate template

International
IR Rectifier

IR WORLD HEADQUARTERS: 101 N. Sepulveda Blvd., El Segundo, California 90245, USA
To contact International Rectifier, please visit <http://www.irf.com/whoto-call/>